REMARKS

The last Office Action of February 12, 2002 has been carefully considered.

It is noted that claims 1-25 are rejected under 35 U.S.C. 103(a) over the patent to Kakizaki in view of the patent to Nagatsuma.

With the present Request for Reconsideration, applicants have amended claims 1 and 9 to more clearly define the present invention. In particular, claims 1 and 9 now contain the subject matter of the original claim 23. In other words these claims define in addition to previous features, the integration and the integration unit. This feature was discussed with the Examiner during the interview and the Examiner expressed his positive attitude toward the prospects of allowance of claims which contain such features.

It is believed that claims 1 and 9 define the features which are not disclosed in the references applied by the Examiner in the final Office Action, and these features can not be derived from the references either taken singly, or in combination with one another. Therefore claims 1 and 9 should be considered as patentably distinguishing over the art and should be allowed.

As for the dependent claims, these claims depend on the independent claims, they share their presumably allowable features, and therefore it is respectfully submitted that they should be allowed as well.

Reconsideration and allowance of present application is most respectfully requested.

Should the Examiner require or consider it advisable that the specification, claims and/or drawings be further amended or corrected in formal respects in order to place this case in condition for final allowance, then it is respectfully requested that such amendments or corrections be carried out by Examiner's Amendment, and the case be passed to issue. Any costs involved should be charged to the deposit account of the undersigned (No. 19-4675). Alternatively, should the Examiner feel that a personal discussion might be helpful in advancing this case to allowance, he is invited to telephone the undersigned (at 631-549-4700).

Respectfully submitted,

Michael J. Striker
Attorney for Applicants
Reg. No. 27233

CLAIMS

Amend the following claims:

1. Method for measuring an electrical voltage, wherein the electrical voltage is an alternating quantity, making use of at least one sensor element (20) and evaluating means (30) by utilizing the Pockets effect and using at least one light source (31) and at least one optical transmission path (OS), wherein a measurement light generated by the light source (31) penetrates an active sensor part (21) comprising at least two sensor crystals at which an electrical voltage drops, and, after the measurement light has traversed the sensor crystals, the polarization state of the measurement light is further used for processing information which, after suitable evaluation, represents a measurement for the electrical voltage dropping over the sensor crystals, wherein the selected quantity of sensor crystals on the measurement path is sufficiently large with respect to the inhomogeneity of the electrical field distribution, and the length of the measurement path is in the same order of magnitude as the length of the path along which the voltage to be measured drops, wherein the evaluating means (30) is used with a corresponding component assembly (40) by means of which the scaling is carried out by multiplying the input signal by a factor which is generated by a function unit, its input quantity representing the difference

between a reference signal and the factored output signal, and wherein the function unit provides integration.

9. Device for measuring the electrical voltage, wherein the electrical voltage is an alternating quantity, and with at least one light source (31) and at least one optical transmission path (OS), at least one sensor element (20) and evaluating means (30) accompanied by the use of the Pockels effect, wherein the sensor element (s) (20) contain(s) at least one active sensor part (21) comprising at least N_{SK} (N_{SK} is greater than or equal to zero) electro-optical sensor crystals (SK_1...SK_N) which are penetrated by a polarized measurement light, wherein the evaluating means (30) contain at least one component assembly (40) by means of which the scaling is carried out by multiplying the input signal by a factor which is generated by a function unit, its input quantity representing the difference between a reference signal and the factor input signal, and wherein the function unit is an integrator.